


<b>Search Notes</b>  	<b>Application/Control No.</b>  10642750	<b>Applicant(s)/Patent Under Reexamination</b>  FUJITA ET AL.
	<b>Examiner</b>  Keefer, Michael E	<b>Art Unit</b>  2154

SEARCHED			
Class	Subclass	Date	Examiner
709	244 (Updated 10/24/2008)	12/11/2006	MEK

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search	12/11/2006	MEK
Consulted Examiner Kevin Bates	5/5/2008	MEK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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